



Oxidation of nickel particles in an environmental TEM

Jeangros, Q.; Hansen, Thomas Willum; Wagner, Jakob Birkedal; Dunin-Borkowski, Rafal E.; Hébert, C.; Van herle, J.; Hessler-Wyser, A.

Publication date:
2013

[Link back to DTU Orbit](#)

Citation (APA):
Jeangros, Q., Hansen, T. W., Wagner, J. B., Dunin-Borkowski, R. E., Hébert, C., Van herle, J., & Hessler-Wyser, A. (2013). *Oxidation of nickel particles in an environmental TEM*. Abstract from Microscopy and Microanalysis 2013, Indianapolis, United States.

General rights

Copyright and moral rights for the publications made accessible in the public portal are retained by the authors and/or other copyright owners and it is a condition of accessing publications that users recognise and abide by the legal requirements associated with these rights.

- Users may download and print one copy of any publication from the public portal for the purpose of private study or research.
- You may not further distribute the material or use it for any profit-making activity or commercial gain
- You may freely distribute the URL identifying the publication in the public portal

If you believe that this document breaches copyright please contact us providing details, and we will remove access to the work immediately and investigate your claim.

Oxidation of nickel particles in an environmental TEM

Q. Jeangros¹, T.W. Hansen², J.B. Wagner², R.E. Dunin-Borkowski³, C. Hébert¹, J. Van herle⁴ and A. Hessler-Wyser¹

¹ Interdisciplinary Centre for Electron Microscopy, Ecole Polytechnique Fédérale de Lausanne, Lausanne, Switzerland.

² Center for Electron Nanoscopy, Technical University of Denmark, Lyngby, Denmark.

³ Ernst Ruska-Centre for Microscopy and Spectroscopy with Electrons and Peter Grünberg Institute, Jülich Research Centre, Jülich, Germany.

⁴ Laboratory for Industrial Energy Systems, Ecole Polytechnique Fédérale de Lausanne, Lausanne, Switzerland.

The mechanisms controlling the growth of an oxide film during oxidation are subject to controversies at intermediate length scales (20-1000 nm) [1]. Relating rate-controlling mechanisms and resulting structural changes, which is essential to the understanding of oxidation processes, has proved challenging under these conditions.

Here, nickel particles are oxidized under 3.2 mbar of O₂ inside an environmental TEM (ETEM) equipped with a post-column filter [2]. Images, diffraction patterns and core-loss electron energy-loss spectra are acquired to monitor the structural and chemical evolution of Ni during oxidation, whilst increasing the temperature up to 600 °C.

Nucleation of NiO on Ni is observed to occur rapidly at room temperature before the introduction of O₂ in the environmental cell (in the vacuum of the microscope). It involves the formation of randomly orientated oxide domains of a few nanometres in size. These domains impinge and cover the particles surface. As the temperature increases under O₂, the NiO film grows and creates irregular structures composed of many crystallites. The reaction kinetics are inferred by EELS using different techniques analyzing changes in shapes of the Ni L_{2,3} white lines [3]. The results indicate that the oxidation process is diffusion-controlled, similarly to results from the literature that were obtained at larger oxide thicknesses [1]. Pores are observed to form at the Ni/NiO interfaces, resulting in the loss of metal/oxide contact (Fig. 1). These observations illustrate that the outward diffusion of Ni²⁺ ions through NiO is the dominant mass transport mechanism under these conditions (in opposition to O₂/O²⁻ transport). Images also indicate that the NiO film might rupture in some regions, a process that should enable some inward diffusion of O₂ and therefore inward growth of NiO. An activation energy for Ni oxidation comparable to the ones found in the literature is determined from our EELS data.

By using ETEM, we are able to relate the structural and chemical changes occurring at the nanoscale during the oxidation of Ni particles with O₂ at high temperature, providing new insights into oxidation/corrosion processes.

[1] A. Atkinson, *Reviews of Modern Physics*, **57** (1985), p. 437.

[2] T.W. Hansen, *et al.*, *Materials Science and Technology*, **26** (2010), p. 1338.

[3] Q. Jeangros, *et al.*, *Acta Materialia*, **58** (2010), p. 4578.

[4] Support from the Swiss National Science Foundation is gratefully acknowledged (project “IN Situ TEM study of reduction and reoxidation of Ni(O)-ceramic composite (INSITE)”).

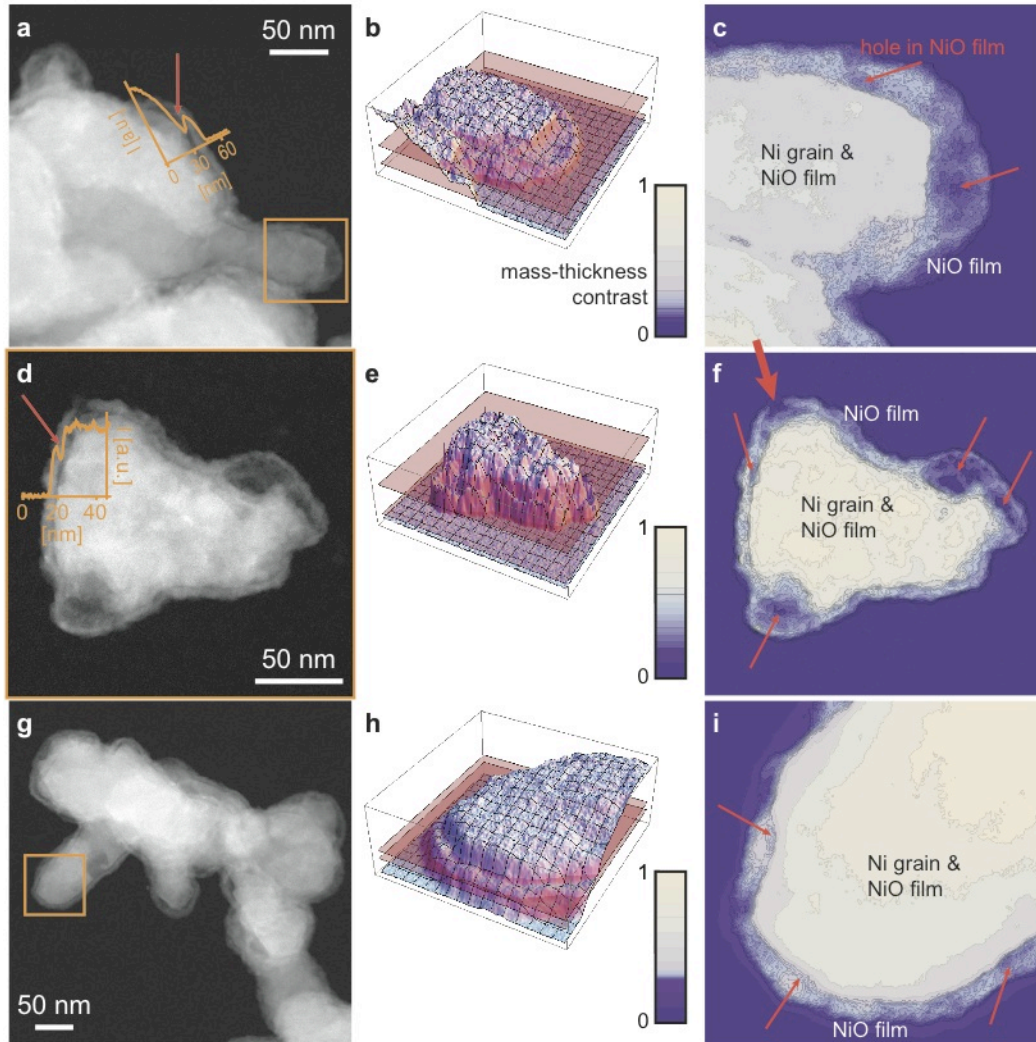


Figure 1: **a**, **d** and **g** STEM-HAADF images of Ni(O) particles at 300 °C under 3.2 mbar of O₂ along with intensity profiles. Arrows highlight a decrease in intensity at the NiO/Ni interfaces. Corresponding 3D histograms and contour plots are shown in **b**, **c**, **e**, **f**, **h** and **i**. The intensity scale of **c**, **f** and **i** has been adapted for each image to illustrate the differences in contrast located between the planes marked in red on the histograms **b**, **e** and **h**. Arrows indicate holes in the NiO film, while the larger one in **f** indicates what seems to be a fracture in the NiO film.